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From 1989-1996 he was a civilian employee with the U.S. Air Force at Newark Air Force Base, Newark, OH, managing and operating a failure analysis lab for semiconductor components. In 1996 he was awarded a Palace Knight position through Wright Patterson Air Force Base (WPAFB), Dayton, OH. Currently, he is a Research Scientist at the Air Force Research Laboratory on WPAFB where his studies focus on the development of nano-materials and their characterization with electron microscopy.

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